

Notice of References Cited	Application/Control No. 09/966,419	Applicant(s)/Patent Under Reexamination VANDENAMEELE-LEPLA, PATRI	
	Examiner Hong Cho	Art Unit 2662	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,796,814 A	08-1998	Brajaj et al.	375/232
	B	US-5,995,499 A	11-1999	Hottinen et al.	370/337
	C	US-6,320,901 B1	11-2001	Arad et al.	375/222
	D	US-2002/0021773 A1	02-2002	Henriksson, Jukka	375/347
	E	US-2002/0027957 A1	03-2002	Paulraj et al.	375/267
	F	US-2002/0039383 A1	04-2002	Zhu et al.	375/214
	G	US-6,442,211 B1	08-2002	Hampel et al.	375/260
	H	US-2002/0122499 A1	09-2002	Kannan et al.	375/260
	I	US-2003/0026223 A1	02-2003	Eriksson et al.	370/335
	J	US-6,765,969 B1	07-2004	Vook et al.	375/259
	K	US-6,826,240 B1	11-2004	Thomas et al.	375/340
	L	US-2005/0002468 A1	01-2005	Walton et al.	375/267
	M	US-6,856,649 B2	02-2005	Birru, Dagnachew	375/233

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

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